

# PHOTOCURRENT IMAGES OF AMORPHOUS-SILICON SOLAR-CELL MODULES

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## State of the Art of a-Si Solar Cells

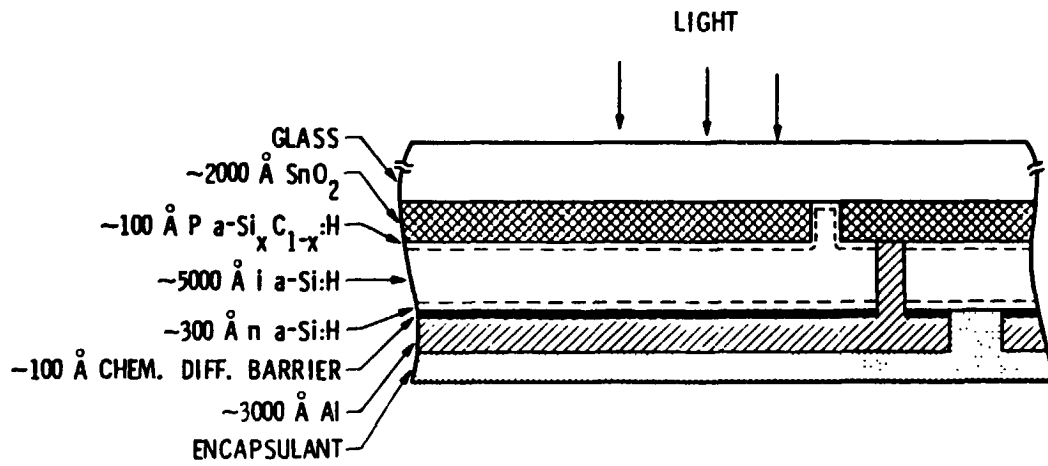
### PERFORMANCE OF BEST REPORTED SINGLE JUNCTION P-I-N AMORPHOUS SILICON SOLAR CELLS

	V <sub>oc</sub> mV	J <sub>sc</sub> mA/cm <sup>2</sup>	FF %	EFF. %
<b>BEST INDIVIDUAL PARAMETERS</b>	950	16.70	74.0	11.70
• HIGH CONVERSION EFFICIENCY:	7.4 - 11.7%			
• DIFFERENT DEVICE STRUCTURES:	p - i - n n - i - p			
• DIFFERENT FABRICATION PROCESS:	GLOW DISCHARGE REACTIVE SPUTTERING CHEMICAL VAPOR DEPOSITION			

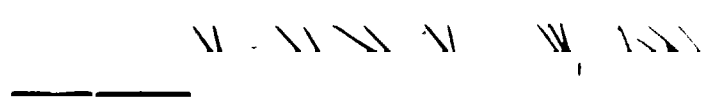
## Commercial Modules

MANUFACTURERS	V <sub>oc</sub> mV	J <sub>sc</sub> mA/cm <sup>2</sup>	FF	EFF. %
A	0.726	9.59	0.572	3.99
B	0.869	12.60	0.666	7.33
C	0.674	13.20	0.717	6.35

a-Si:H Solar-Cell Structure With Enlarged Section of  
Electrode Coupling Portion of Integrated a-Si Cell



MODULE DEVELOPMENT AND ENGINEERING SCIENCES ORIGINAL PAGE IS  
OF POOR QUALITY  
Module A and Its Cell Intercoupling

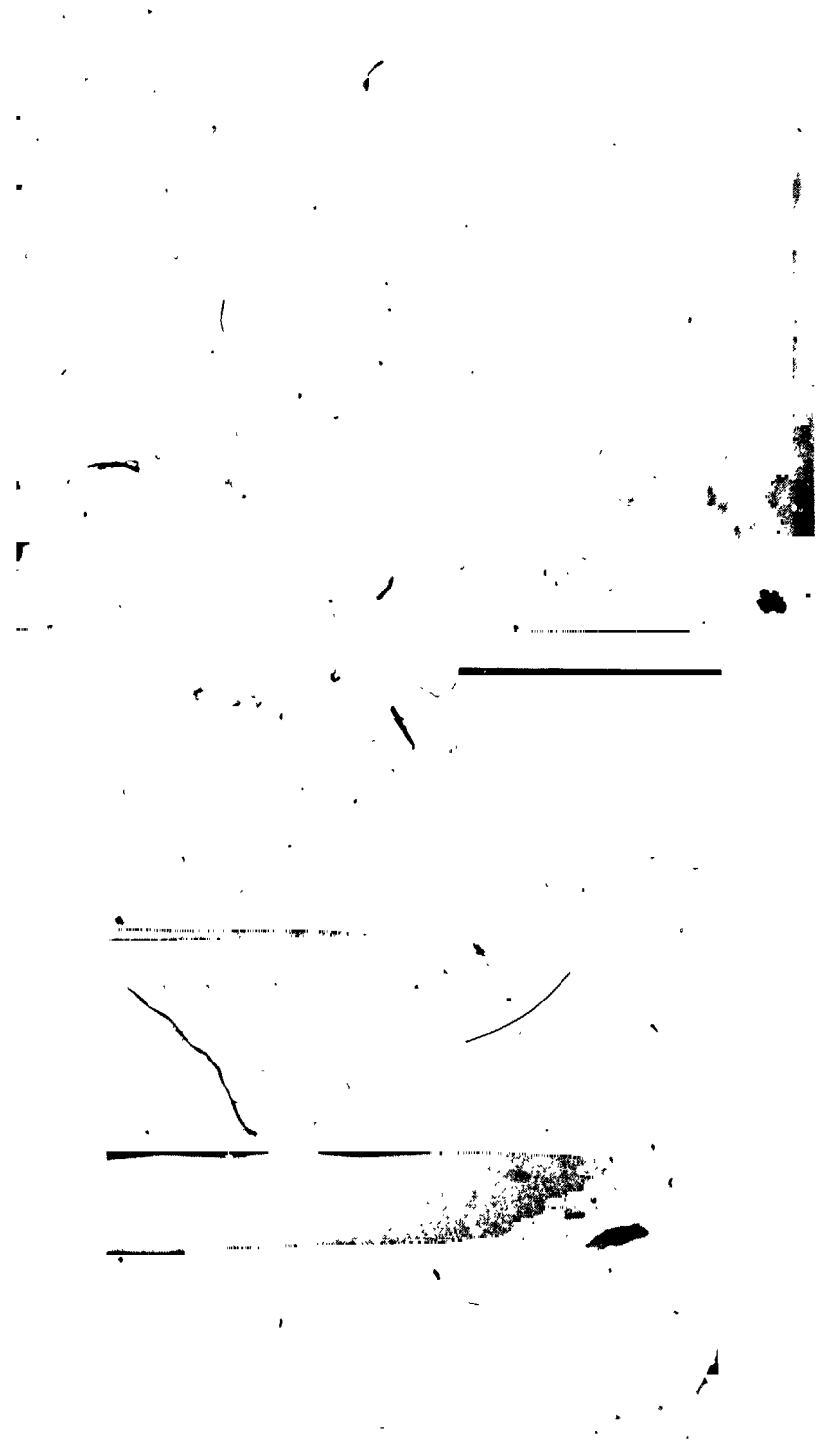


MODULE DEVELOPMENT AND ENGINEERING SCIENCES

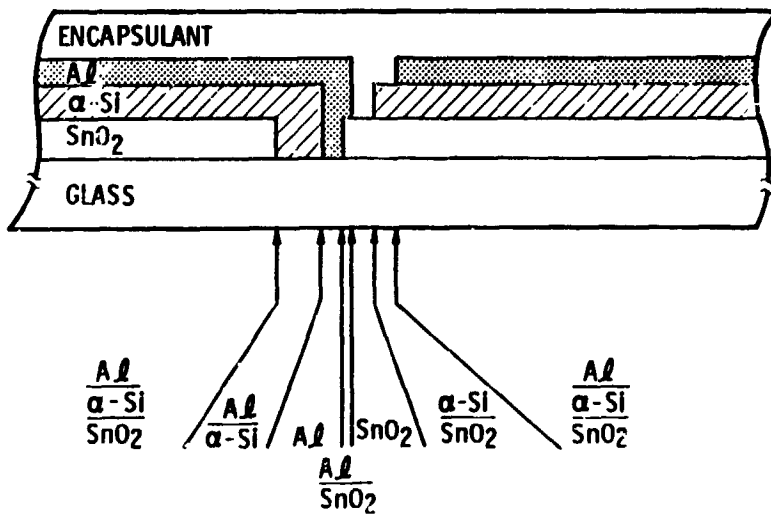
Module B and Its Cell Intercoupling



Module C and Its Cell Intercoupling



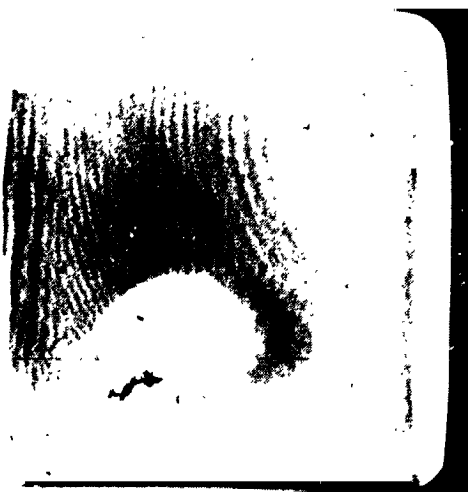
a-Si:H Solar-Cell Structure With Enlarged Section of Masked Cell Interconnecting Portion



Failure Modes

- ELECTRICAL SHORTS
- FILM INHOMOGENITY
- CELL INTER-COUPLING WORKMANSHIP
- EFFICIENCY DEGRADATION
- WEATHERING DUE TO:
  - TEMPERATURE
  - HUMIDITY
  - CORROSION
  - ETC.

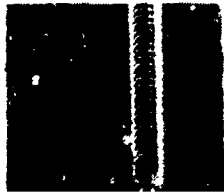
Electrical Short



Masking Problem

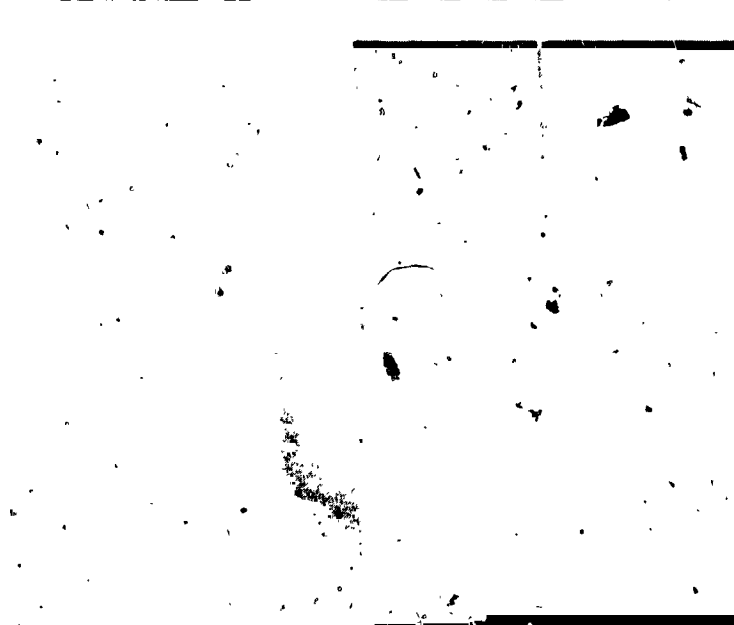
MODULE DEVELOPMENT AND ENGINEERING SCIENCES

Non-Uniform Laser Scribing



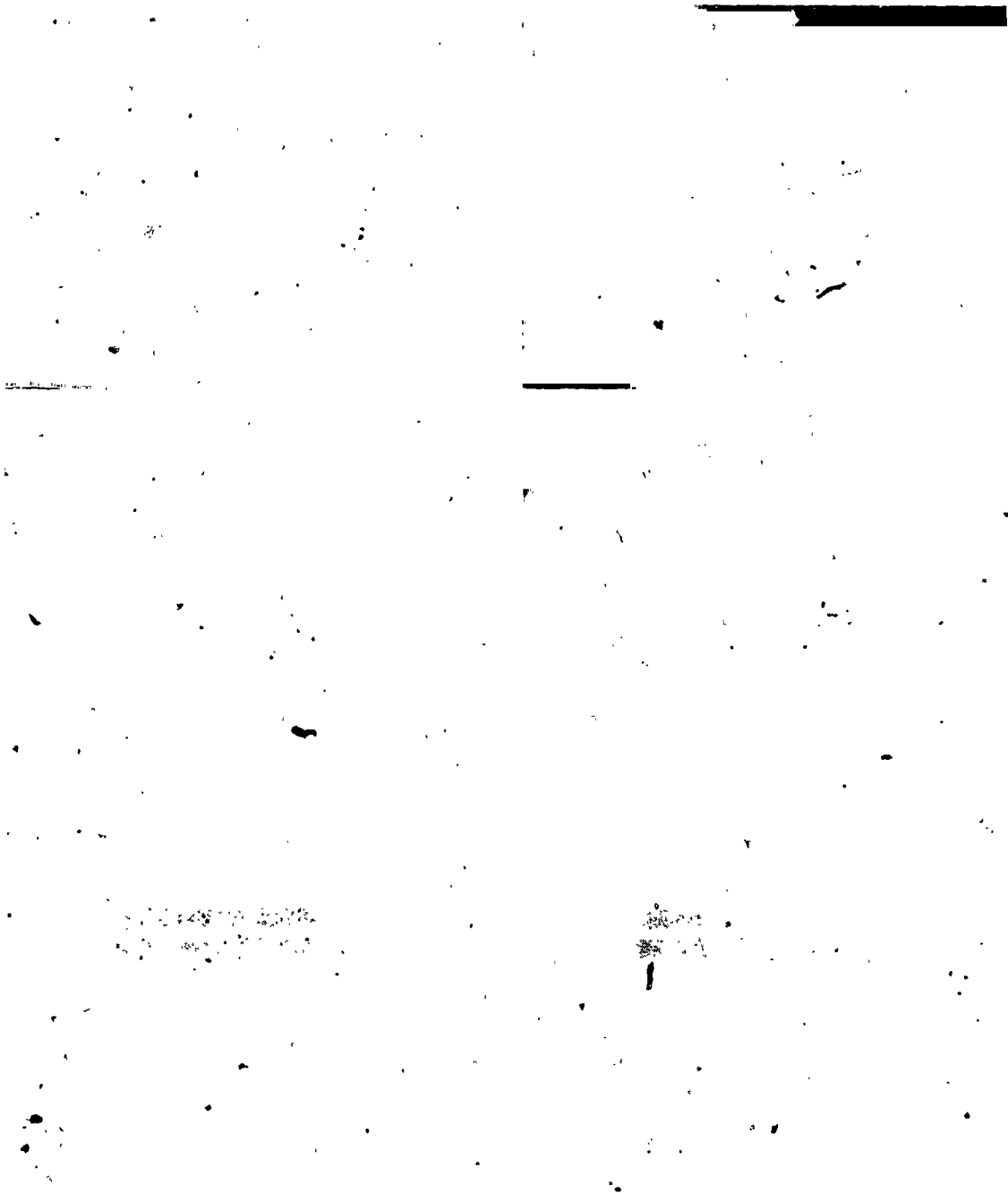


Masking Workmanship



MODULE DEVELOPMENT AND ENGINEERING SCIENCES

Y-Modulation for Better Display



NORMAL

Y-MODULATED

MODULE DEVELOPMENT AND ENGINEERING SCIENCES

Solar-Cell Laser Scanner Images

ORIGINAL PAGE IS  
OF POOR QUALITY

MODULE A

MODULE B

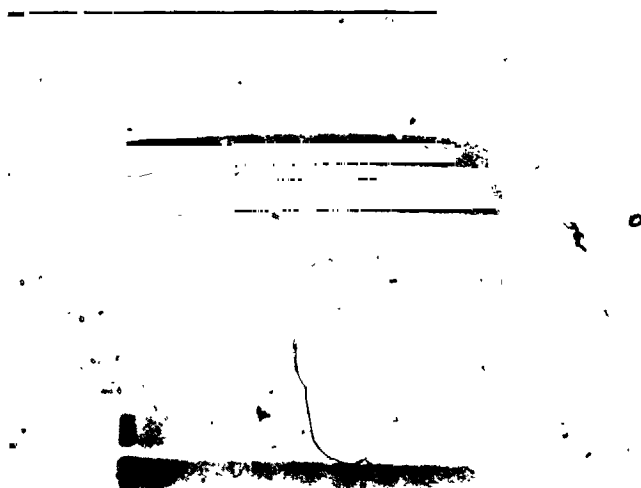
MODULE C

# MODULE DEVELOPMENT AND ENGINEERING SCIENCES

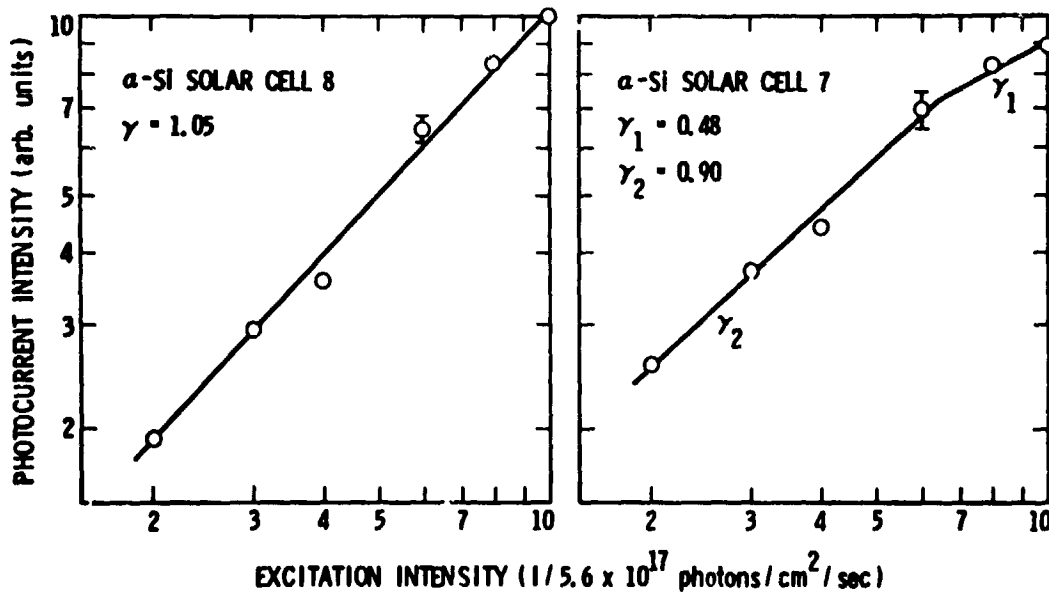
## Effects of Excitation Intensity on Photocurrent Response

- PROCESS V.S. CELL QUALITY
- NONDESTRUCTIVE DIAGNOSIS ON PROCESSING PARAMETERS

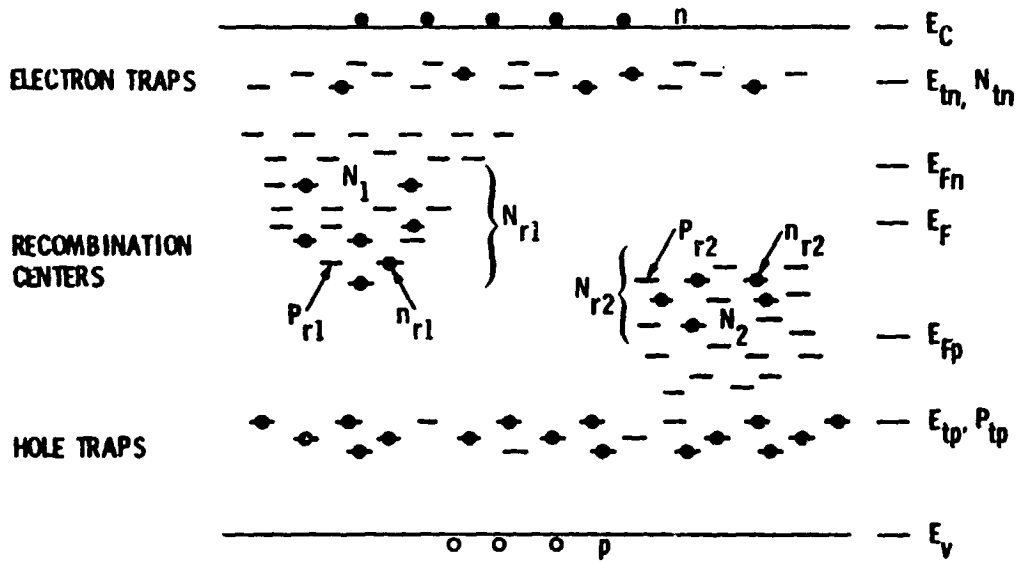
### SCLS Image of Module 1 Using 4579 Å Argon Laser Line



### Photocurrent Dependence on Excitation Intensity



Schematic Energy-Band Diagram and Distribution of Gap States in a-Si:H



$n_r$  = RECOMBINATION CENTERS OCCUPIED BY ELECTRONS  
 $p_r$  = RECOMBINATION CENTERS EMPTY OF ELECTRONS  
 $n_r + p_r = N_r$

Free Carrier Electron Transport Model

$1 \geq \gamma \geq \frac{1}{2}$  : MONOMOLECULAR RECOMBINATION

$$I = F^\gamma$$

$\gamma = \frac{1}{2}$  : BIMOLECULAR RECOMBINATION

(DIRECT RECOMBINATION BETWEEN EITHER  
 FREE OR TRAPPED CARRIERS)

Whisker Signal

- DEVICE PARAMETER RELATED
- PROCESS RELATED

Conclusion

- SOLAR CELL LASER SCANNER CAN BE EFFECTIVELY USED TO NONDESTRUCTIVELY TEST NOT ONLY ACTIVE DEFECTS BUT ALSO THE CELL QUALITY AND INTEGRITY OF ELECTRICAL CONTACTS.

Plans for a-Si Solar Cells

- UPGRADE SCLS CAPABILITY TO PROBE PHOTOCURRENT RESPONSE IN DIFFERENT LAYERS OF THE DEVICE.
- EVALUATE AND CHARACTERIZE MODULE DEGRADATIONAL PHENOMENA IN THIN-FILM AMORPHOUS SILICON SOLAR CELLS WITH PARTICULAR EMPHASIS ON MICRO AND MACROSCOPIC DEFECTS/FLAWS.
- DEVELOP METHODS TO ANALYZE FAILURE MODES RESULTING FROM DEGRADATION DUE TO ENVIRONMENTAL EFFECTS SUCH AS OPTICAL, THERMAL, MECHANICAL AND MOISTURE.
- ANALYZE CELL INTER-COUPPLINGS.

Photocurrent Signal of Module 1 Across the  
Nine Cells in Series Coupled Module Scanned  
by a He-Ne Laser (3.0 mW)

